TOSHIBA Transistor Silicon NPN Epitaxial Type (PCT Process)

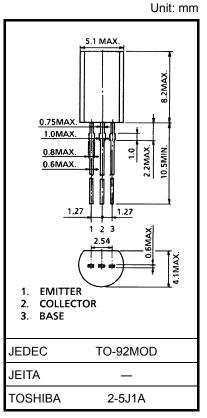
# 2SC2500

# Strobe Flash Applications Medium-Power Amplifier Applications

- $\bullet \quad \mbox{High DC}$  current gain and excellent  $\mbox{hFE}$  linearity
  - $h_{FE}(1) = 140 \text{ to } 600 \text{ (V}_{CE} = 1 \text{ V}, I_{C} = 0.5 \text{ A})$
  - $h_{FE}(2) = 70 \text{ (min)}, 200 \text{ (typ.)}, \text{ (VCE} = 1 \text{ V, IC} = 2 \text{ A)}$
- Low saturation voltage: VCE (sat) = 0.5 V (max) (IC = 2 A, IB = 50 mA)

#### Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		$V_{CBO}$	30	V	
Collector-emitter voltage		V <sub>CES</sub>	30	V	
		V <sub>CEO</sub>	10		
Emitter-base voltage		V <sub>EBO</sub>	6	V	
Collector current	DC	Ic	2	А	
	Pulsed (Note 1)	I <sub>CP</sub>	5		
Base current		IB	0.5	Α	
Collector power dissipation		PC	900	mW	
Junction temperature		Tj	150	°C	
Storage temperature range		T <sub>stg</sub>	-55 to 150	°C	



Weight: 0.36 g (typ.)

Note 1: Pulse test: Pulse width = 10 ms (max), duty cycle = 30% (max)

Note 2: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

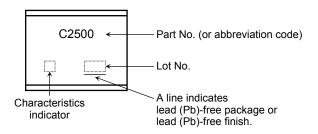
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

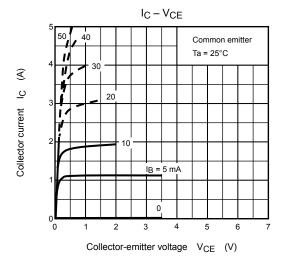
## **Electrical Characteristics (Ta = 25°C)**

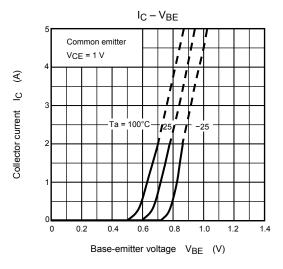
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I <sub>CBO</sub>	V <sub>CB</sub> = 30 V, I <sub>E</sub> = 0	_	_	100	nA
Emitter cut-off current	I <sub>EBO</sub>	V <sub>EB</sub> = 6 V, I <sub>C</sub> = 0	_	_	100	nA
Collector-emitter breakdown voltage	V <sub>CEO</sub>	I <sub>C</sub> = 10 mA, I <sub>B</sub> = 0	10	_	_	٧
Emitter-base breakdown voltage	V <sub>EBO</sub>	I <sub>C</sub> = 1 mA, I <sub>C</sub> = 0	6	_	_	٧
DC current gain	h <sub>FE (1)</sub> (Note 3)	V <sub>CE</sub> = 1 V, I <sub>C</sub> = 0.5 A	140	_	600	
	h <sub>FE (2)</sub>	V <sub>CE</sub> = 1 V, I <sub>C</sub> = 2 A	70	200	_	
Collector-emitter saturation voltage	V <sub>CE</sub> (sat)	I <sub>C</sub> = 2 A, I <sub>B</sub> = 50 mA	_	0.2	0.5	V
Base-emitter voltage	V <sub>BE</sub>	V <sub>CE</sub> = 1 V, I <sub>C</sub> = 2 A	_	0.86	1.5	V
Transition frequency	f <sub>T</sub>	V <sub>CE</sub> = 1 V, I <sub>C</sub> = 0.5 A	_	150	_	MHz
Collector output capacitance	C <sub>ob</sub>	V <sub>CB</sub> = 10 V, I <sub>E</sub> = 0, f = 1 MHz	_	27	_	pF

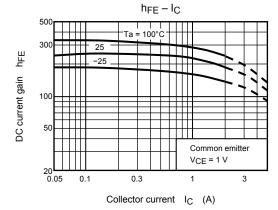
Note 3: h<sub>FE (1)</sub> classification A: 140 to 240, B: 200 to 330, C: 300 to 450, D: 420 to 600

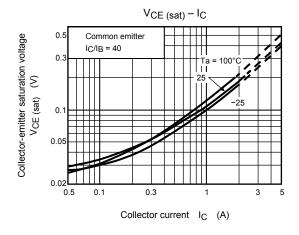
### Marking

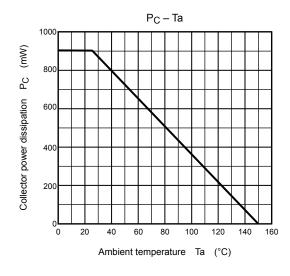


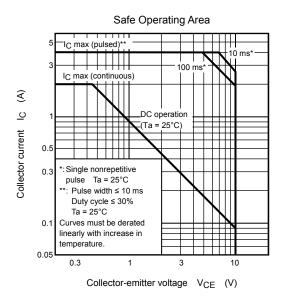












3

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